

Notice of References Cited	Application/Control No. 10/507,466	Applicant(s)/Patent Under Reexamination OSTERMEIER, MARK	
	Examiner Shin-Lin Chen	Art Unit 1632	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,596,485	07-2003	Anderson et al.	435/6
	B	US-			
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	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	Kratz et al., 1999, PNAS, Vol. 96, pp. 1915-1920.
	V	Lacatena et al., 1994, PNAS, Vol. 91, pp. 10521-10525.
	W	Doi et al., 1999, FEBS Letters, Vol. 453, p. 305-307.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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